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CORRECTION

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Correction: Strain mapping inside an individual processed vertical nanowire transistor using scanning X-ray nanodiffraction

Dmitry Dzhigaev,*[a] Johannes Svensson,[b] Abinaya Krishnaraja,[b] Zhongyunshen Zhu,[b] Zhe Ren,[a] Yi Liu,[a] Sebastian Kalbfleisch,[c] Alexander Björling,[c] Filip Lenrick,[a] Zoltan Imre Balogh,[d] Susanna Hammarberg,[a] Jesper Wallentin,[a] Rainer Timm,[a] Lars-Erik Wernersson[b] and Anders Mikkelsen[a]

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The authors regret that the Acknowledgements section in the original manuscript was incorrect. The Acknowledgements should read as follows:

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The Royal Society of Chemistry apologises for these errors and any consequent inconvenience to authors and readers.

[a]*Division of Synchrotron Radiation Research and NanoLund, Department of Physics, Lund University, P.O. Box 118, SE-221 00 Lund, Sweden. E-mail: dmitry.dzhigaev@sljus.lu.se*
[b]*Electrical and Information Technology, Department of Engineering, Lund University, P.O. Box 118, SE-221 00 Lund, Sweden*
[c]*MAX IV Laboratory, Lund University, 22100 Lund, Sweden*
[d]*DTU CEN, DTU, Fysikvej 2800, Lyngby, Denmark*